

Search Notes

Application/Control No.

10/777,026

Examiner

Binh X. Tran

Applicant(s)/Patent under
Reexamination

KAWAGUCHI ET AL.

Art Unit

1765

SEARCHED

Class	Subclass	Date	Examiner
216	68	5/9/2006	BT
216	69	5/9/2006	BT
216	73	5/9/2006	BT

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventors' name using USPAT, USPG-PUB, JPO, EPO, DERWENT databases	5/9/2006	BT